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# ***Passive Millimeter-Wave Imaging Technology XIV***

**David A. Wikner  
Arttu R. Luukanen**  
*Editors*

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# Contents

vii *Conference Committee*

---

## SESSION 1 IMAGING SYSTEMS

---

- 8022 02 **Millimeter-wave interferometric radiometry for the detection and geolocation of low-power signals** [8022-01]  
D. J. Dowgiallo, E. M. Twarog, S. Rauhen, W. M. Peters, U.S. Naval Research Lab. (United States); T. J. Lazio, Jet Propulsion Lab. (United States); N. R. McGlothlin, Praxis, Inc. (United States); J. F. Helmboldt, P. W. Gaiser, U.S. Naval Research Lab. (United States)
- 8022 03 **Progress toward a video-rate, passive millimeter-wave imager for brownout mitigation** [8022-02]  
D. G. Mackrides, C. A. Schuetz, R. D. Martin, T. E. Dillon, P. Yao, Phase Sensitive Innovations, Inc. (United States); D. W. Prather, Univ. of Delaware (United States)
- 8022 04 **Towards high-sensitivity and high-resolution submillimeter-wave video imaging** [8022-03]  
E. Heinz, T. May, D. Born, G. Zieger, S. Anders, V. Zakosarenko, Institute of Photonic Technology (Germany); M. Schubert, Supracon AG (Germany); T. Krause, A. Krüger, M. Schulz, H.-G. Meyer, Institute of Photonic Technology (Germany)
- 8022 05 **Improved reconstruction and sensing techniques for personnel screening in three-dimensional cylindrical millimeter-wave portal scanning** [8022-04]  
J. L. Fernandes, Pacific Northwest National Lab. (United States); C. M. Rappaport, Northeastern Univ. (United States); D. M. Sheen, Pacific Northwest National Lab. (United States)
- 8022 06 **High-resolution passive video-rate imaging at 350 GHz** [8022-05]  
D. Becker, National Institute of Standards and Technology (United States); C. Gentry, The Univ. of Oklahoma (United States); P. Ade, Cardiff Univ. (United Kingdom); J. Beall, H.-M. Cho, National Institute of Standards and Technology (United States); S. Dicker, Univ. of Pennsylvania (United States); W. Duncan, National Institute of Standards and Technology (United States); M. Halpern, Univ. of British Columbia (Canada); G. Hilton, K. Irwin, P. Lowell, M. Niemack, N. Paulter, C. Reintsema, F. Schima, R. Schwall, National Institute of Standards and Technology (United States); C. Tucker, Cardiff Univ. (United Kingdom)
- 8022 07 **Design and performance of a passive video-rate THz system demonstrator** [8022-06]  
A. Luukanen, Millimetre-Wave Lab. of Finland (Finland) and VTT Technical Research Ctr. of Finland (Finland); M. Aikio, M. Grönholm, M. M. Leivo, A. Mäyrä, A. Rautiainen, H. Toivanen, VTT Technical Research Ctr. of Finland (Finland)
- 8022 08 **A new approach for fast security scanning with millimetre-waves: SARGATE** [8022-07]  
S. A. Lang, M. Högelen, J. Ender, S. Hantscher, H. Essen, Fraunhofer Institute for High Frequency Physics and Radar Techniques (Germany)

- 8022 09 **Multi-sensor millimeter-wave system for hidden objects detection by non-collaborative screening** [8022-08]  
R. Zouaoui, R. Czarny, F. Diaz, THALES (France); A. Khy, Institut Telecom ParisTech (France); T. Lamarque, THALES (France)
- 8022 0A **300 GHz imaging with 8 meter stand-off distance and one-dimensional synthetic image reconstruction** [8022-09]  
A. Keil, T. Loeffler, H. Quast, SynView GmbH (Germany); V. Krozer, Goethe Univ. (Germany); J. Dall, A. Kusk, V. Zhurbenko, T. Jensen, Technical Univ. of Denmark (Denmark); P. de Maagt, European Space Research and Technology Ctr. (Netherlands)
- 8022 0B **3D rendering of passive millimeter-wave scenes using modified open source software** [8022-10]  
M. Murakowski, J. Wilson, J. Murakowski, G. Schneider, Univ. of Delaware (United States); C. Schuetz, Phase Sensitive Innovations, Inc. (United States); D. Prather, Univ. of Delaware (United States)

---

## SESSION 2 PHENOMENOLOGY

---

- 8022 0C **Phenomenology studies using a scanning fully polarimetric passive W-band millimeter-wave imager** [8022-11]  
B. E. Bernacki, J. F. Kelly, D. M. Sheen, D. L. McMakin, J. R. Tedeschi, T. E. Hall, B. K. Hatchell, P. L. J. Valdez, Pacific Northwest National Lab. (United States)
- 8022 0D **Impact of frequency and polarization diversity on a terahertz radar's imaging performance** [8022-12]  
K. B. Cooper, R. J. Dengler, Jet Propulsion Lab. (United States); N. Llombart, Univ. Complutense de Madrid (Spain)
- 8022 0E **Investigation of fully-polarimetric signatures from targets with some relevance to security applications** [8022-26]  
M. Peichl, S. Dill, D. Rudolf, Deutsches Zentrum für Luft- und Raumfahrt e.V. (Germany)
- 8022 0G **Pulsed terahertz bi-directional reflection distribution function (BRDF) measurements of materials and obscurants** [8022-14]  
S.-Z. A. Lo, National Institute of Standards and Technology (United States) and Univ. of Maryland at College Park (United States); D. Novotny, E. N. Grossman, E. J. Heilweil, National Institute of Standards and Technology (United States)
- 8022 0H **Calibration, reconstruction, and rendering of cylindrical millimeter-wave image data** [8022-15]  
D. M. Sheen, T. E. Hall, Pacific Northwest National Lab. (United States)

---

## SESSION 3 DEVICES AND INTELLIGENT SENSING

---

- 8022 0I **Compressive sampling in passive millimeter-wave imaging** [8022-16]  
N. Gopalsami, T. W. Elmer, S. Liao, R. Ahern, A. Heifetz, A. C. Raptis, Argonne National Lab. (United States); M. Luessi, D. Babacan, A. K. Katsaggelos, Northwestern Univ. (United States)

- 8022 OJ **Two-dimensional, real-time, sub-millimeter-wave imaging using a spatially selective mask** [8022-17]  
O. Furxhi, E. L. Jacobs, R. Hewitt, The Univ. of Memphis (United States)
- 8022 OK **Compressive sensing for a sub-millimeter-wave single pixel imager** [8022-18]  
I. Noor, O. Furxhi, E. L. Jacobs, The Univ. of Memphis (United States)
- 8022 OL **A multi-camera positioning system for steering of a THz stand-off scanner** [8022-19]  
M. Axelsson, M. Karlsson, S. Rudner, Swedish Defence Research Agency (Sweden)
- 8022 OM **Rapid beamsteering reflectarrays for mm-wave and submm-wave imaging radars** [8022-20]  
A. Luukanen, VTT Technical Research Ctr. of Finland (Finland); J. Ala-Laurinaho, Aalto Univ. (Finland); D. Gomes Martins, J. Häkli, P. Koivisto, P. Pursula, P. Rantakari, J. Säily, VTT Technical Research Ctr. of Finland (Finland); A. Tamminen, Aalto Univ. (Finland); R. Tuovinen, M. Sipilä, VTT Technical Research Ctr. of Finland (Finland)
- 8022 ON **A 220 GHz reflection-type phased array concept study** [8022-21]  
A. S. Hedden, C. R. Dietlein, D. A. Wikner, U.S. Army Research Lab. (United States)
- 8022 OO **W-band direct detection radiometers using metamorphic HEMT technology** [8022-22]  
I. Kallfass, Fraunhofer Institute for Applied Solid-State Physics (Germany) and Karlsruhe Institute of Technology (Germany); A. Huelsmann, A. Tessmann, A. Leuther, E. Weissbrodt, M. Schlechtweg, Fraunhofer Institute for Applied Solid-State Physics (Germany); O. Ambacher, Fraunhofer Institute for Applied Solid-State Physics (Germany) and Univ. of Freiburg (Germany)

---

#### POSTER SESSION

- 8022 OQ **An ethics of body scanners: requirements and future challenges from an ethical point of view** [8022-24]  
B. Rampp, A. F. X. Wolkenstein, R. Ammicht Quinn, Tübingen Univ. (Germany)

*Author Index*



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